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We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China







Operational Amplifiers, High Slew Rate, Low Voltage, Rail-to-Rail Output

The NCS2003 family of op amps features high slew rate, low voltage operation with rail–to–rail output drive capability. The 1.8 V operation allows high performance operation in low voltage, low power applications. The fast slew rate and wide unity–gain bandwidth (5 MHz at 1.8 V) make these op amps suited for high speed applications. The low input offset voltage (4 mV max) allows the op amp to be used for current shunt monitoring. Additional features include no output phase reversal with overdriven inputs and ultra low input bias current of 1 pA.

The NCS2003 family is the ideal solution for a wide range of applications and products. The single channel NCS2003, dual channel NCS20032, and quad channel NCS20034 are available in a variety of compact and space—saving packages. The NCV prefix denotes that the device is AEC—Q100 Qualified and PPAP Capable.

Features

- Unity Gain Bandwidth: 7 MHz at $V_S = 5 \text{ V}$
- Fast Slew Rate: 8 V/ μ s rising, 12.5 V/ μ s falling at V_S = 5 V
- Rail-to-Rail Output
- No Output Phase Reversal for Over–Driven Input Signals
- Low Offset Voltage: 0.5 mV typical
- Low Input Bias Current: 1 pA typical
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb–Free, Halogen Free/BFR Free and are RoHS Compliant

Applications

- Current Shunt Monitor
- Signal Conditioning
- Active Filter
- Sensor Buffer

End Products

- Motor Control Drives
- Hard Drives
- Medical Devices
- White Goods and Air Conditioners



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MARKING DIAGRAMS

ANxYW=

8 8 8 8 8

2K32 AYW■

20032

ALYWX

H H H

K32

A =

¹⁴<u>A A A A A A A</u>

YWW



SOT23-5 CASE 483 (NCS/NCV2003)



SOT553, 5 LEAD CASE 463B (NCS2003)



Micro8[™] DM SUFFIX CASE 846A



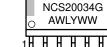
SOIC-8 CASE 751



TSSOP-8 T SUFFIX CASE 948S



SOIC-14 NB CASE 751A



A = Assembly Location

WL, L = Wafer Lot

Y = Year WW, W = Work Week

G or ■ = Pb–Free Package

(Note: Microdot may be in either location)

ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 2 of this data sheet.

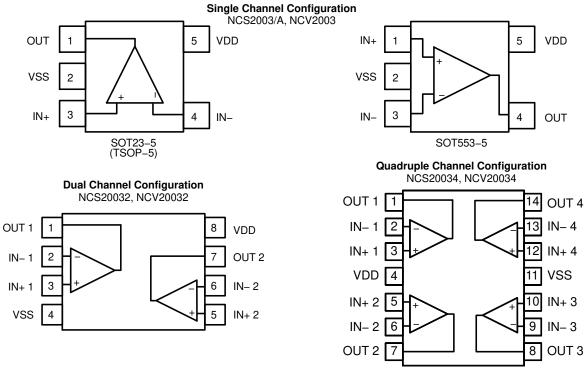


Figure 1. Pin Connections

ORDERING INFORMATION

Device	Configuration	Automotive	Marking	Package	Shipping [†]
NCS2003SN2T1G	Single	No	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003ASN2T1G		No	AN4	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS2003XV53T2G		No	А3	SOT553-5 (Pb-Free)	4000 /Tape and Reel
NCV2003SN2T1G*		Yes	AN3	SOT23-5 (Pb-Free)	3000 / Tape and Reel
NCS20032DMR2G	Dual	No	2K32	Micro8 (Pb–Free)	4000 / Tape and Reel
NCS20032DR2G			20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCS20032DTBR2G			K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCV20032DMR2G*		Yes	2K32	Micro8 (Pb–Free)	4000 / Tape and Reel
NCV20032DR2G*			20032	SOIC-8 (Pb-Free)	2500 / Tape and Reel
NCV20032DTBR2G*			K32	TSSOP-8 (Pb-Free)	3000 / Tape and Reel
NCS20034DR2G	Quad	No	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel
NCV20034DR2G*		Yes	NCS20034G	SOIC-14 (Pb-Free)	2500 / Tape and Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D

^{*}NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable.

ABSOLUTE MAXIMUM RATINGS

Over operating free-air temperature, unless otherwise stated

Parameter		Symbol	Limit	Unit
Supply Voltage (V _{DD} – V _{SS})		V _S	7.0	V
INPUT AND OUTPUT PINS				
Input Voltage (Note 1)		V _{IN}	V _{SS} – 0.3 to 7.0	V
Input Current		I _{IN}	10	mA
Output Short Current (Note 2)		Io	100	mA
TEMPERATURE				
Storage Temperature		T _{STG}	-65 to 150	°C
Junction Temperature		TJ	150	°C
ESD RATINGS (Note 3)				
Human Body Model	NCx2003, A NCx20032 NCx20034	НВМ	3000 2000 3000	V
Machine Model	NCx2003, A NCx20032 NCx20034	ММ	200 100 150	V
Charged Device Model	NCx2003, A NCx2003x	CDM	1000 2000	V
OTHER PARAMETERS				
Moisture Sensitivity Level (Note 5)		MSL	Level 1	
Latch-up Current (Note 4)		I _{LU}	100	mA

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- Neither input should exceed the range of V_{SS} 300 mV to 7.0 V. This device contains internal protection diodes between the input pins and V_{DD}. When V_{IN} exceeds V_{DD}, the input current should be limited to the specified value.
- Indefinite duration; however, maximum package power dissipation limits must be observed to ensure that the maximum junction temperature is not exceeded.
- 3. This device series incorporates ESD protection and is tested by the following methods:
 - ESD Human Body Model tested per AEC-Q100-002 and JESD22-A114
 - ESD Machine Model tested per AEC-Q100-003 and JESD22-A115
 - ESD Charged Device Model tested per AEC-Q100-011 and ANSI/ESD S5.3.1-2009
- 4. Latch-up current tested per JEDEC Standard JESD78.
- 5. Moisture Sensitivity Level tested per IPC/JEDEC standard J-STD-020A.

THERMAL INFORMATION

Thermal Metric	Symbol	Package	Single Layer Board (Note 6)	Multi Layer Board (Note 7)	Unit
		SOT23-5/TSOP-5	408	355	
	θЈА	SOT553-5	428	406	
Junction to Ambient		Micro8/MSOP8	235	163	00/14/
Thermal Resistance		SOIC-8	240	179	°C/W
		TSSOP-8	300	238	
		SOIC-14	167	123	

- 6. Values based on a 1S standard PCB according to JEDEC51-3 with 1.0 oz copper and a 300 mm² copper area
- 7. Values based on a 1S2P standard PCB according to JEDEC51–7 with 1.0 oz copper and a 100 mm² copper area

RECOMMENDED OPERATING CONDITIONS

Para	meter	Symbol	Min	Max	Unit
Operating Supply Voltage (V _{DD} – V _{SS})		V _S	1.7	5.5	V
Specified Operating Range	NCS2003, A NCV2003, NCx20032, NCx20034	T _A	-40 -40	+85 +125	°C
Input Common Mode Range		V _{CM}	V _{SS}	V _{DD} -0.6	V

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

ELECTRICAL CHARACTERISTICS: V_S = +1.8 V

At $T_A = +25^{\circ}C$, $R_L = 10~k\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit	
INPUT CHARACTERISTICS	1					'		
Input Offset Voltage	V _{OS}	NCS2003A			0.5	3.0	mV	
		NCx2003, NCx20032, NCx20034			0.5	4.0	mV	
						5.0	mV	
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$				2.0		μV/°C	
		NCS2003A (No	te 8)			6.0	μV/°C	
Input Bias Current	I _{IB}				1		pA	
Input Offset Current	I _{OS}				1		pA	
Channel Separation	XTLK	DC, NCx20032, NC	Cx20034		100		dB	
Input Resistance	R _{IN}				1		TΩ	
Input Capacitance	C _{IN}				1.2		pF	
Common Mode Rejection	CMRR	$V_{IN} = V_{SS}$ to V_{DD}	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V		80		dB	
Ratio		$V_{IN} = V_{SS} + 0.2 \text{ V to } V_{DD} - 0.6 \text{ V}$		65			ĺ	
OUTPUT CHARACTERISTIC	cs				•			
Open Loop Voltage Gain	A _{VOL}	$R_L = 10 \text{ k}\Omega$		80	92		dB	
				75				
		$R_L = 2 k\Omega$			92			
				70				
Output Current Capability	I _{SC}	Sourcing		5	8		mA	
(Note 8)		Sinking		10	14		İ	
Output Voltage High	V _{OH}	$R_L = 10 \text{ k}\Omega$		1.75	1.798		V	
		$R_L = 2 k\Omega$		1.7	1.78		ĺ	
Output Voltage Low	Vol	R _L = 10 kΩ	NCx2003, A		7	50	mV	
			NCx2003x		7	100		
		$R_L = 2 k\Omega$			20	100	İ	
NOISE PERFORMANCE				I				
Voltage Noise Density	e _N	f = 1 kHz			20		nV/√ Hz	
Current Noise Density	i _N	f = 1 kHz			0.1		pA√ Hz	
DYNAMIC PERORMANCE				I				
Gain Bandwidth Product	GBWP				5		MHz	
		Rising Edge, $R_L = 2 \text{ k}\Omega$, $A_V = +1$ Falling Edge, $R_L = 2 \text{ k}\Omega$, $A_V = +1$			6			
Slew Rate at Unity Gain	SR -				9		V/μs	
Phase Margin	Ψm	R _L = 10 kΩ, C _L =	$R_L = 10 \text{ k}\Omega, C_L = 5 \text{ pF}$		53		0	
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$	NCx2003, A		12		dB	
	111		NCx2003x		8		1	
Settling Time	t _S	$V_O = 1 \text{ Vpp},$ Gain = 1, $C_L = 20 \text{ pF}$	Settling time to 0.1%		1.8		μs	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

8. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +1.8 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit	
DYNAMIC PERORMANCE							
Total Harmonics Distortion +	THD+N	$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	r = +1, f = 1 kHz		0.005		%
Noise		$V_O = 1 V_{pp}, R_L = 2 k\Omega, A_V$	= +1, f = 10 kHz		0.025		
POWER SUPPLY							
Power Supply Rejection Ratio	Power Supply Rejection Ratio PSRR NCx2003			72	80		dB
				65			
	•	NCx20032, NCx	20034	80	100		
Quiescent Current	I _{DD}	No load, per channel	NCx2003, A		230	560	μΑ
						1000	
			NCx20032,		275	375	
			NCx20034			575	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

8. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} = \text{midsupply}$, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions	Min	Тур	Max	Unit
INPUT CHARACTERISTICS	S					
Input Offset Voltage	V _{OS}	NCS2003A		0.5	3.0	mV
		NCx2003		0.5	4.0	mV
		NCx20032, NCx20034			5.0	mV
Offset Voltage Drift	$\Delta V_{OS}/\Delta T$			2.0		μV/°C
		NCS2003A (Note 9)			6.0	μV/°C
Input Bias Current	I _{IB}			1		рА
Input Offset Current	I _{OS}			1		рА
Channel Separation	XTLK	DC, NCx20032, NCx20034		100		dB
Input Resistance	R _{IN}			1		TΩ
Input Capacitance	C _{IN}			1.2		pF

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10~k\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditi	ons	Min	Тур	Max	Unit
INPUT CHARACTERISTICS	•	1	,		1		1
Common Mode Rejection Ratio	CMRR	NCx2003, A	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	65	90		dB
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	63			
		NCx20032, NCx20034	$V_{IN} = V_{SS}$ to $V_{DD} - 0.6$ V	70	90		
			$V_{IN} = V_{SS} + 0.2 \text{ V}$ to $V_{DD} - 0.6 \text{ V}$	65			
OUTPUT CHARACTERISTICS							
Open Loop Voltage Gain	A _{VOL}	R _L = 10	kΩ	86	92		dB
				78			
		R _L = 2	kΩ	83	92		
				78			
Output Current Capability	I _{SC}	Sourcing		40	76		mA
(Note 9)		Sinking		50	96		
Output Voltage High	V _{OH}	$R_L = 10 \text{ k}\Omega$		4.95	4.99		V
		$R_L = 2 k\Omega$		4.9	4.97		
Output Voltage Low	Vol	R _L = 10 kΩ	NCx2003, A		8	50	mV
			NCx2003x		8	100	
		R _L = 2	kΩ		24	100	
NOISE PERFORMANCE							
Voltage Noise Density	e _N	f = 1 k	Hz		20		nV/√ Hz
Current Noise Density	i _N	f = 1 k	Hz		0.1		pA√ Hz
DYNAMIC PERORMANCE							
Gain Bandwidth Product	GBWP				7		MHz
Slew Rate at Unity Gain	SR	Rising Edge, R _L =	2 kΩ, AV = +1		8		V/μs
		Falling Edge, R _L =	2 kΩ, AV = +1		12.5		
Phase Margin	Ψm	$R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$	NCx2003, A		64		۰
			NCx2003x		56		
Gain Margin	A _m	$R_L = 10 \text{ k}\Omega$, (C _L = 5 pF		9		dB
Settling Time	t _S	$V_{O} = 1 V_{pp},$ Gain = 1, $C_{L} = 20 pF$	Settling time to 0.1%		0.6		μS
Total Harmonics Distortion +	THD+N	$V_O = 4 V_{pp}, R_L = 2 k\Omega,$	$A_V = +1, f = 1 \text{ kHz}$		0.002		%
Noise			$V_{O} = 4 V_{pp}, R_{L} = 2 k\Omega, A_{V} = +1, f = 10 \text{ kHz}$		0.01		

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

9. Guaranteed by design and/or characterization.

ELECTRICAL CHARACTERISTICS: V_S = +5.0 V

At $T_A = +25^{\circ}C$, $R_L = 10~k\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range. Guaranteed by design and/or characterization.

Parameter	Symbol	Conditions		Min	Тур	Max	Unit
POWER SUPPLY							
Power Supply Rejection Ratio	PSRR	NCx2003, A		72	80		dB
				65			
		NCx20032, N	Cx20034	80	100		
Quiescent Current	I _{DD}	No load, per channel	NCx2003, A		300	660	μΑ
						1000	
NCx20032,			325	450			
			NCx20034			675	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 9. Guaranteed by design and/or characterization.

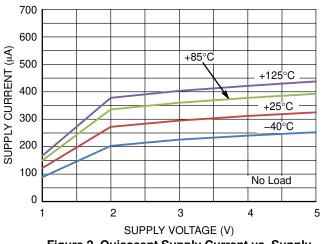


Figure 2. Quiescent Supply Current vs. Supply Voltage

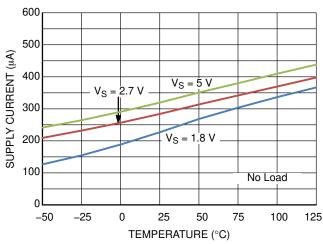


Figure 3. Quiescent Supply Current vs. Temperature

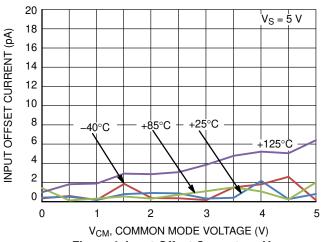


Figure 4. Input Offset Current vs. V_{CM}

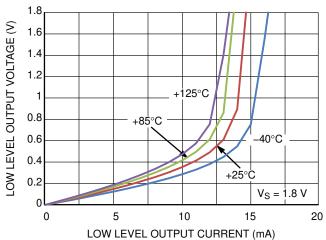


Figure 5. Low Level Output Voltage vs. Output Current @ V_S = 1.8 V

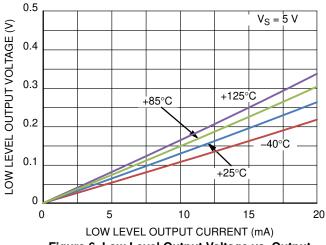


Figure 6. Low Level Output Voltage vs. Output Current @ $V_S = 5 \text{ V}$

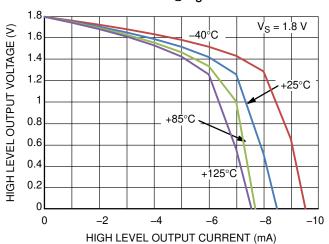


Figure 7. High Level Output Voltage vs. Output Current @ $V_S = 1.8 \text{ V}$

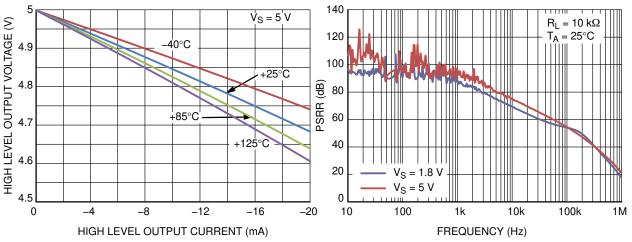


Figure 8. High Level Output Voltage vs. Output Current @ $V_S = 5 \text{ V}$

Figure 9. PSRR vs. Frequency

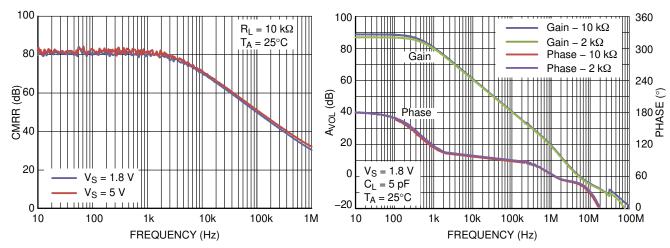


Figure 10. CMRR vs. Frequency

Figure 11. Open Loop Gain and Phase vs. Frequency @ $V_S = 1.8 \text{ V}$

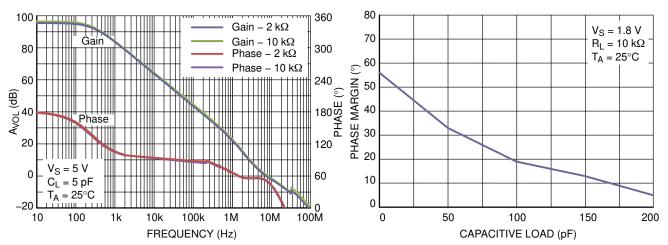
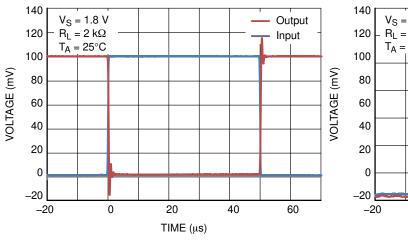


Figure 12. Open Loop Gain and Phase vs. Frequency @ V_S = 5 V

Figure 13. Phase Margin vs. Capacitive Load



TIME (μs)
Figure 14. Inverting Small Signal Transient Response

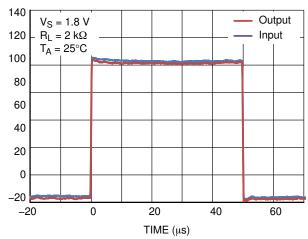


Figure 15. Non-Inverting Small Signal Transient Response

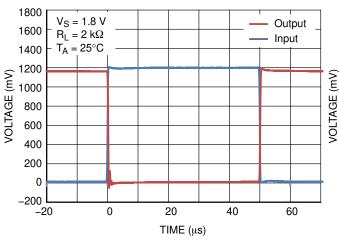


Figure 16. Inverting Large Signal Transient Response

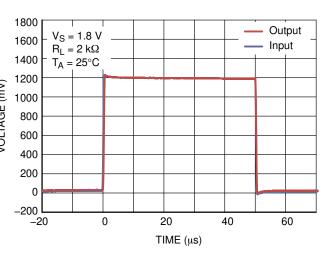


Figure 17. Non-Inverting Large Signal Transient Response

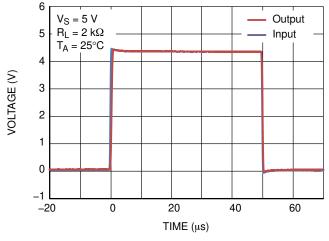


Figure 18. Non-Inverting Large Signal Transient Response

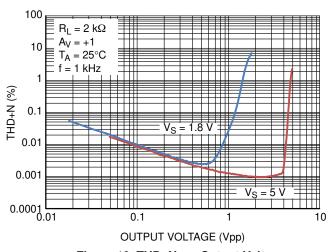
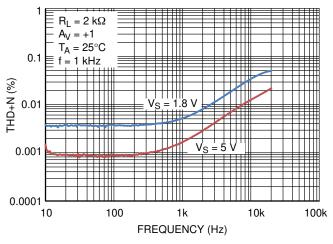


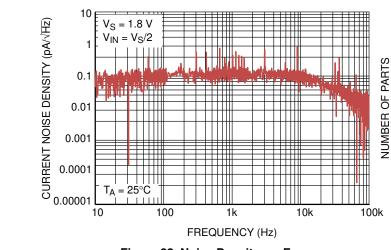
Figure 19. THD+N vs. Output Voltage



140 120 VOLTAGE NOISE (nV/√Hz) 25°C 100 80 60 40 20 0 10 100 1k 10k 100k FREQUENCY (Hz)

Figure 20. THD+N vs. Frequency

Figure 21. Input Voltage Noise vs. Frequency



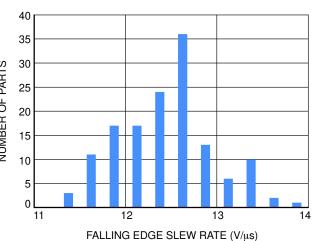
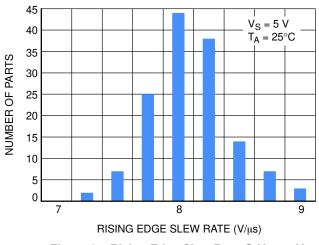


Figure 22. Noise Density vs. Frequency

Figure 23. Falling Edge Slew Rate @ Vs = 5 V



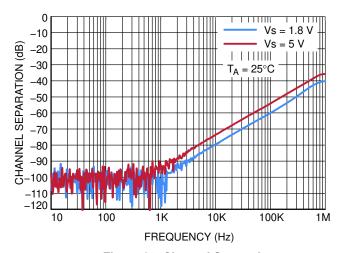
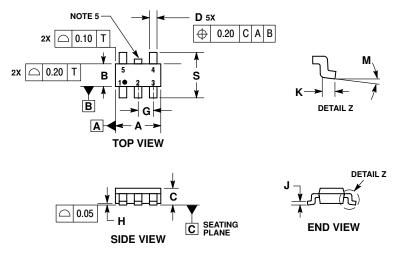


Figure 24. Rising Edge Slew Rate @ Vs = 5 V

Figure 25. Channel Separation

PACKAGE DIMENSIONS

TSOP-5 CASE 483-02 ISSUE K



- NOTES:

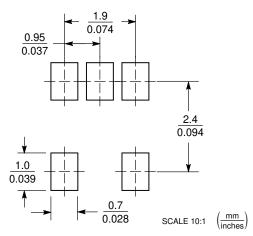
 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.

 2. CONTROLLING DIMENSION: MILLIMETERS.

- CONTROLLING DIMENSION: MILLIMETERS.
 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE
 MINIMUM THICKNESS OF BASE MATERIAL.
 DIMENSIONS A AND B DO NOT INCLUDE MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS. MOLD
 FLASH, PROTRUSIONS, OR GATE BURRS. SHALL NOT
 EXCEED 0.15 PER SIDE. DIMENSION A.
 DETIONAL CONSETRICTION: AN ADDITIONAL
- OPTIONAL CONSTRUCTION: AN ADDITIONAL TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

	MILLIN	IETERS
DIM	MIN	MAX
Α	3.00	BSC
В	1.50	BSC
С	0.90	1.10
D	0.25	0.50
G	0.95	BSC
Н	0.01	0.10
J	0.10	0.26
K	0.20	0.60
M	0 °	10°
S	2.50	3.00

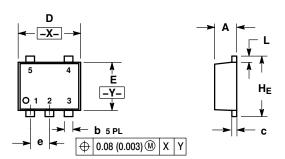
SOLDERING FOOTPRINT*



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

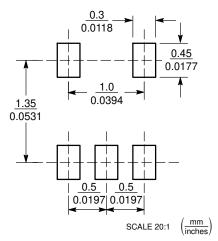
SOT-553, 5 LEAD CASE 463B ISSUE C



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 2. CONTROLLING DIMENSION: MILLIMETERS
 3. MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE MINIMUM
 THICKNESS OF BASE MATERIAL.

	М	ILLIMETE	RS		INCHES		
DIM	MIN	NOM	MAX	MIN	NOM	MAX	
Α	0.50	0.55	0.60	0.020	0.022	0.024	
b	0.17	0.22	0.27	0.007	0.009	0.011	
С	0.08	0.13	0.18	0.003	0.005	0.007	
D	1.55	1.60	1.65	0.061	0.063	0.065	
E	1.15	1.20	1.25	0.045	0.047	0.049	
е		0.50 BSC		0.020 BSC			
L	0.10	0.20	0.30	0.004	0.008	0.012	
HE	1.55	1.60	1.65	0.061	0.063	0.065	

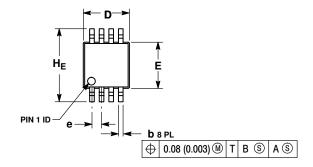
RECOMMENDED SOLDERING FOOTPRINT*

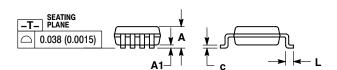


*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

Micro8™ CASE 846A-02 **ISSUE J**





NOTES:

- IOTES:

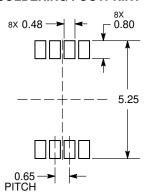
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A DOES NOT INCLUDE MOLD FLASH, PROTRUSIONS OR GATE BURRS, MOLD FLASH, PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED A 14 (20.00) PER DIST.
- MOLD FLASH, PROTHOSIONS OR GATE BURRS SHALL NOT EACEED
 0.15 (0.006) PER SIDE.
 MOLD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.
 846A-01 OBSOLETE, NEW STANDARD 846A-02.

	MILLIMETERS INCHES					
DIM	MIN	NOM	MAX	MIN	NOM	MAX
Α			1.10			0.043
A1	0.05	0.08	0.15	0.002	0.003	0.006
b	0.25	0.33	0.40	0.010	0.013	0.016
С	0.13	0.18	0.23	0.005	0.007	0.009
D	2.90	3.00	3.10	0.114	0.118	0.122
E	2.90	3.00	3.10	0.114	0.118	0.122
е		0.65 BSC			0.026 BSC)
L	0.40	0.55	0.70	0.016	0.021	0.028
HE	4.75	4.90	5.05	0.187	0.193	0.199

RECOMMENDED SOLDERING FOOTPRINT*

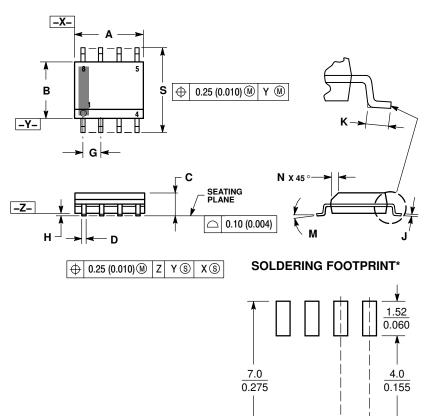


DIMENSION: MILLIMETERS

^{*}For additional information on our Pb–Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07 **ISSUE AK**



0.6

0.024

NOTES:

- NOTIES:

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

 3. DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.

 4. MAXIMUM MOLD PROTRUSION 0.15 (0.006) DED SIDE PER SIDE.
- PER SIDE.
 DIMENSION D DOES NOT INCLUDE DAMBAR
 PROTRUSION. ALLOWABLE DAMBAR
 PROTRUSION SHALL BE 0.127 (0.005) TOTAL
 IN EXCESS OF THE D DIMENSION AT
 MAXIMUM MATERIAL CONDITION.
 751-01 THRU 751-06 ARE OBSOLETE. NEW
 STANDARD IS 751-07.

	MILLIMETERS		INCHES		
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
C	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27 BSC		0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
Κ	0.40	1.27	0.016	0.050	
M	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

1.270

0.050

SCALE 6:1

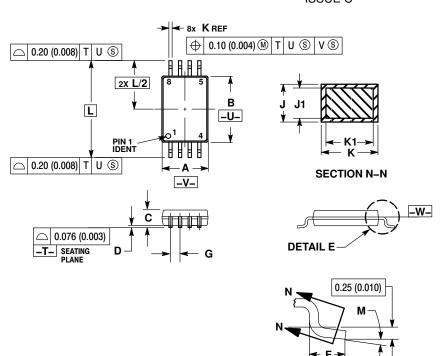
 $\left(\frac{\text{mm}}{\text{inches}}\right)$

^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

PACKAGE DIMENSIONS

TSSOP-8 CASE 948S ISSUE C

DETAIL E



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A DOES NOT INCLUDE MOLD FLASH.
 PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15
- (0.006) PER SIDE.

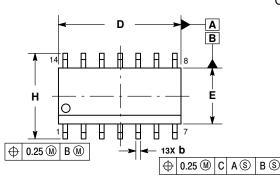
 4. DIMENSION B DOES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010)
- PER SIDE.
 5. TERMINAL NUMBERS ARE SHOWN FOR
- REFERENCE ONLY.

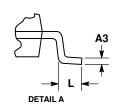
 6. DIMENSION A AND B ARE TO BE DETERMINED AT DATUM PLANE -W-.

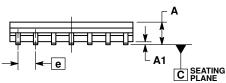
	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	2.90	3.10	0.114	0.122
В	4.30	4.50	0.169	0.177
С		1.10		0.043
D	0.05	0.15	0.002	0.006
F	0.50	0.70	0.020	0.028
G	0.65 BSC		0.026 BSC	
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40 BSC		0.252 BSC	
M	0°	8°	0°	8°

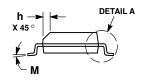
PACKAGE DIMENSIONS

SOIC-14 NB CASE 751A-03 ISSUE K







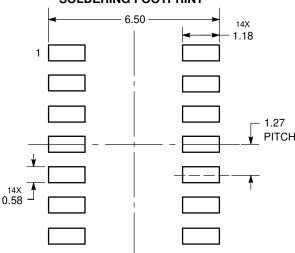


NOTES:

- DIMENSIONING AND TOLERANCING PER
 ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
- 3. DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.
- 5. MAXIMUM MOLD PROTRUSION 0.15 PER SIDE.

	MILLIN	IETERS	INCHES	
DIM	MIN	MAX	MIN	MAX
Α	1.35	1.75	0.054	0.068
A1	0.10	0.25	0.004	0.010
А3	0.19	0.25	0.008	0.010
b	0.35	0.49	0.014	0.019
D	8.55	8.75	0.337	0.344
Е	3.80	4.00	0.150	0.157
е	1.27 BSC		0.050 BSC	
Н	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.019
Ĺ	0.40	1.25	0.016	0.049
M	0 °	7°	0 °	7°

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

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